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## **Nanotechnologies — Characterization of single-wall carbon nanotubes using near infrared photoluminescence spectroscopy**

*Nanotechnologies — Caractérisation de nanotubes de carbone  
monofeuillet en utilisant la spectroscopie de photoluminescence dans  
le proche infra-rouge*



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## Foreword

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This document was prepared by Technical Committee ISO/TC 229, *Nanotechnologies*.

This second edition cancels and replaces the first edition (ISO/TS 10867:2010), which has been technically revised.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

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## Introduction

The discovery of the band-gap photoluminescence (PL) of single-wall carbon nanotubes (SWCNTs) has provided a useful method to characterize their unique electronic properties induced by their low-dimensionality. This method is described in this document.